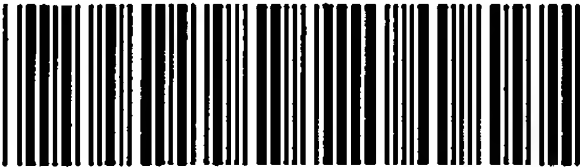


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/807,364	LAI, HAN-CHUNG	
	<b>Examiner</b>	<b>Art Unit</b>	
	Kenneth A. Parker	2871	

SEARCHED			
Class	Subclass	Date	Examiner
349	54	9/11/2005	KP
✓	46	✓	✓

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR